

Search Notes

Application/Control No.

10/786,093

Examiner

Seung H. Lee

Applicant(s)/Patent under
Reexamination

TOYAMA ET AL.

Art Unit

2876

SEARCHED

Class	Subclass	Date	Examiner
235	462.35,46 2.41,462.4 2	3/1/2006	SHL
235	455	3/1/2006	SHL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Same as	Above	3/1/2006	SHL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
235/454,472.01(see printouts)	3/1/2006	SHL
PCT cites	3/1/2006	SHL
NPL	3/1/2006	SHL